

The Analytical Imaging Facility Presents:

New Innovations in Array Tomography and Correlative Light and Electron Microscopy

Speakers: Vinnie Cavaliere, Kyle Crosby, Tanay Desai, and Geoff Perumal of Carl Zeiss Microscopy, LLC.

Monday, April 24th 2017, at 11am in Forchheimer 614

In this talk, we will discuss new advances and innovations from ZEISS in the areas of Scanning Electron Microscopy, specifically with regards to Correlative Light and Electron Microscopy (CLEM), and Array Tomography of large sample areas. Our discussion will focus on new advances in these areas, specifically in Cryo-CLEM utilizing a high resolution confocal detector known as Airyscan in tandem with present cryo-SEM techniques, and in Array Tomography of large sample areas, employing simultaneous scanning of 61 or 91 electron beams in a new kind of multi-beam SEM known as "MultiSEM." We will be available after the presentation to answer questions for further discussion.

